

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	((("6062225") or ("6331659"))).PN.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:42
L2	626	(600/310).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:42
L3	3335	(128/922,898).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:43
L4	395	(250/363.02).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:43
L5	1530	(435/2).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:43
L6	399	(800/14,24).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:43
L7	280	(377/10).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:44
L8	6544	2 or 3 or 4 or 5 or 6 or 7	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/22 14:44
L9	269	8 and retard\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/22 14:44
L10	9	8 and (retard\$4 same imag\$4)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/22 14:44
S1	0	retard\$4 near3 "3nm"	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/22 11:50
S2	0	retard\$4 same "3nm"	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:55
S3	200	retard\$4 same imag\$4 same intensity	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:56
S4	5	S3 and spindle	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:58
S5	88	meiotic near2 spindle	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:59

S6	0	S5 and retardance	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:59
S7	17	S5 and retard\$5	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 12:01
S8	160125	retard\$5	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 12:01
S9	3713	retardance	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 13:03
S10	19	oocyte same retard\$5	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:14
S11	0	meiotic same spindle same oocyte same structure same retardance	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:15
S12	0	meiotic same spindle same oocyte same structure same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:15
S13	0	meiotic same oocyte same structure same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:16
S14	1	meiotic same oocyte same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:17
S15	2	((("6062255") or ("6331659"))).PN.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/19 14:19
S16	2	((("6062225") or ("6331659"))).PN.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/19 14:19
S17	30	("2022164" "2495878" "2623367" "2809800" "3254504" "3456803" "3608579" "3982406" "4207994" "4436109" "4577657" "4599166" "4776952" "4792059" "4946599" "5003790" "5045197" "5064097" "5083442" "5244009" "5269442" "5285815" "5336406" "5607083").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2004/11/19 14:20
S18	0	spindle same retardance same image	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:22
S19	1	spindle same retardance same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:26

S20	0	retardance same sensitivit\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:26
S21	55	retardance same sensitivit\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:34
S22	0	S21 and meiotic	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:27
S23	1	spindle same retardance	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:37
S24	7	spindle same meiotic same mammalian same oocyte	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:40
S25	2	S24 and retard\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:38
S26	2093	spindle same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:40
S27	0	S26 same retardacne	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:41
S28	0	S26 and retardacne	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:41
S29	22	S26 and retarda\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:41

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1 Maximization of information content in polarimetric measurements

Tyo, J.S.;

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2 Imaging polarimetry with an micro-retarder array

Kikuta, H.; Numata, K.; Arimitsu, H.; Iwata, K.; Kato, N.;

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4 A new generation tree retardant insulation compound for medium

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